

RoHS COMPLIANT

AP92U03GMT-HF-VB Datasheet N-Channel 30 V (D-S) MOSFET

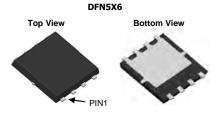
PRODUCT SUMMARY						
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^{a, e}	Q _g (Typ.)			
30	0.003 at V _{GS} = 10 V	120	71 nC			
	0.005 at V _{GS} = 4.5 V	90	71110			

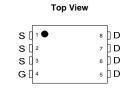
FEATURES

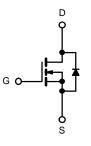
- Trench Power MOSFET
- 100 % R_g and UIS Tested ٠

APPLICATIONS

- Notebook PC Core
- VRM/POL •







N-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	V _{GS} ± 20	
	T _C = 25 °C		120 ^{a, e}	
Continuous Drain Current (T _J = 175 °C)	T _C = 70 °C		90 ^e	
Continuous Drain Current $(1) = 175$ C)	T _A = 25 °C	. I _D	21 ^{b, c}	A
	T _A = 70 °C		20.8 ^{b, c}	
Pulsed Drain Current		I _{DM}	250	
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	56	
Single Pulse Avalanche Energy		E _{AS}	60	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	I _S	80 ^{a, e}	Α
Continuous Source-Drain Diode Current	T _A = 25 °C		76 ^{b, c}	
	T _C = 25 °C		210 ^a	
Maximum Power Dissipation	T _C = 70 °C	P _D	155	w
Maximum Power Dissipation	T _A = 25 °C		35 ^{b, c}	vv
	T _A = 70 °C	[13 ^{b, c}	
Operating Junction and Storage Temperature R	ange	T _J , T _{stg}	- 55 to 175	°C

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ s}$	R _{thJA}	41	50	°C/W		
Maximum Junction-to-Case	Steady State	R _{thJC}	0.7	0.9	°C/vv		

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 s.

d. Maximum under steady state conditions is 90 °C/W.

e. Calculated based on maximum junction temperature. Package limitation current is 80 A.

Parameter	Symbol	Min .	Тур.	Max.	Unit	
Static		Test Conditions				
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	- 050 A		35		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \ \mu A$	1.0		2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
	I _{DSS}	$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1	
Zero Gate Voltage Drain Current		V _{DS} = 30 V, V _{GS} = 0 V, T _J = 55 °C			10	μΑ
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	80			Α
	Б	V _{GS} = 10 V, I _D = 32 A		0.003		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 29 A		0.005		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 32 A		130		S
Dynamic ^b			•		•	
Input Capacitance	C _{iss}				3200	
Output Capacitance	C _{oss}	V_{DS} = 12.5 V, V_{GS} = 0 V, f = 1 MHz			1025	pF
Reverse Transfer Capacitance	C _{rss}				970	
Total Gate Charge	Q _g Q _{gs}	$V_{DS} = 15 \text{ V}, \text{ V}_{GS} = 10 \text{ V}, \text{ I}_{D} = 32 \text{ A}$			71	nC
Iotal Gale Charge					61.5	
Gate-Source Charge		V_{DS} = 15 V, V_{GS} = 4.5 V, I_D = 29 A			34	
Gate-Drain Charge	Q _{gd}				29	
Gate Resistance	Rg	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.555 Ω		11	17	- - - ns -
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 27$ A, V_{GEN} = 10 V, R_g = 1 Ω		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	
Rise Time	t _r	V_{DD} = 15 V, R_L = 0.625 Ω		180	270	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ 24 A, V_{GEN} = 4.5 V, R_g = 1 Ω		55	83	
Fall Time	t _f			12	18	
Drain-Source Body Diode Characteristic	s		•		•	
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			80	A
Pulse Diode Forward Current ^a	I _{SM}				100	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$I_{-} = 20$ A di/dt = 100 A/up T = 25 °C		70.2	105	nC
Reverse Recovery Fall Time	t _a	I _F = 20 A, di/dt = 100 A/μs, T _J = 25 °C		27		
Reverse Recovery Rise Time	t _b			25		ns

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

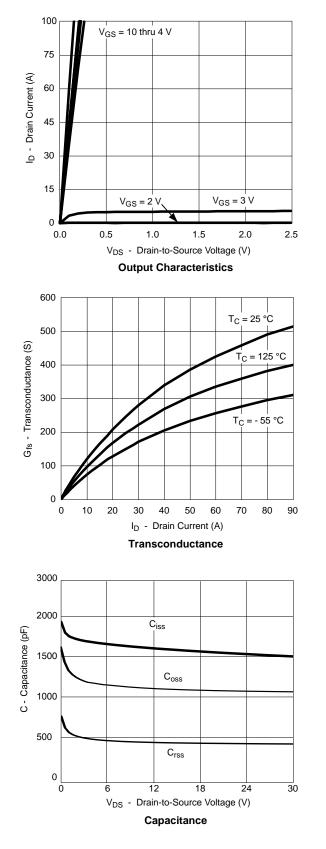
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

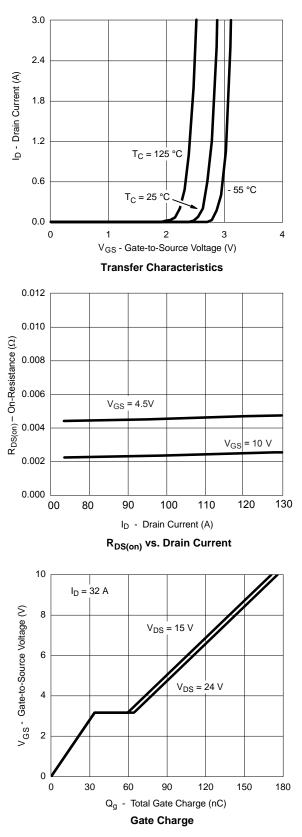
Bsemi

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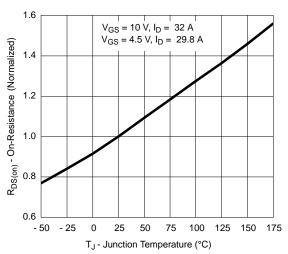


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

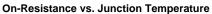


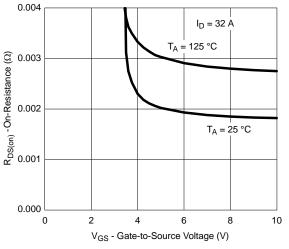


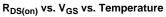




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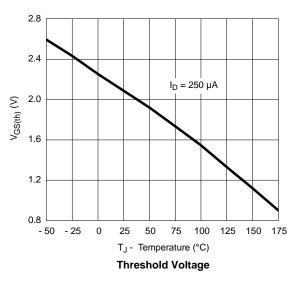


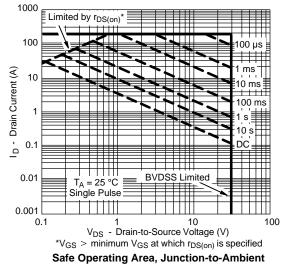




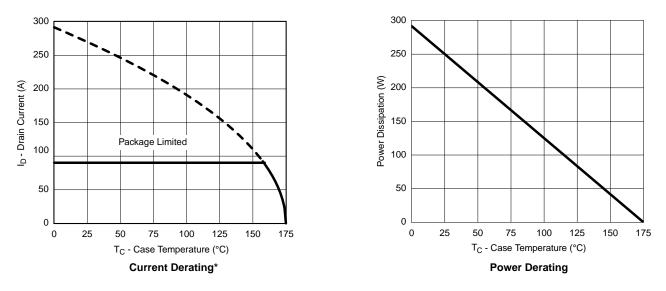






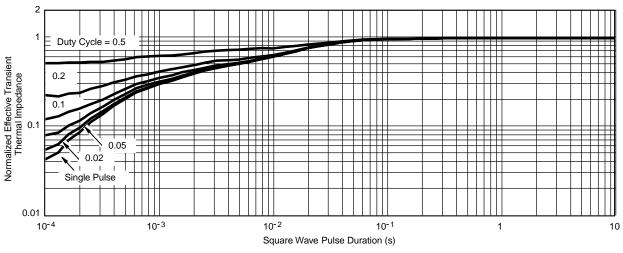






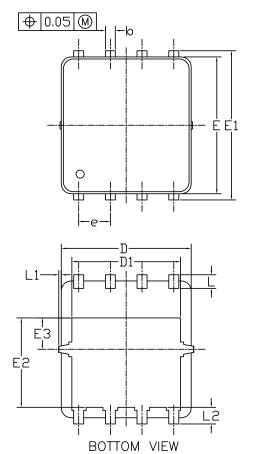
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

* The power dissipation P_D is based on $T_{J(max)} = 175 \text{ °C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

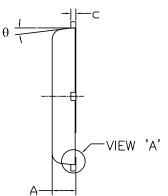


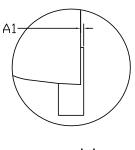
Normalized Thermal Transient Impedance, Junction-to-Case





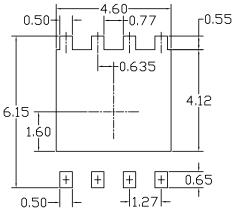
DFN5x6_8L_EP1_P PACKAGE OUTLIN





<u>VIEW 'A'</u> (SCALE 5:1)

RECOMMENDED LAND PATTERN



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
SYMBOLS	MIN	NOM	MAX	MIN	NOM	MAX
A	0.85	0.95	1.00	0.033	0.037	0.039
Al	0.00		0.05	0.000		0.002
b	0.30	0.40	0.50	0.012	0.016	0.020
c	0.15	0.20	0.25	0.006	0.008	0.010
D	5.10	5.20	5.30	0.201	0.205	0.209
D1	4.25	4.35	4.45	0.167	0.171	0.175
E	5.45	5.55	5.65	0.215	0.219	0.222
E1	5.95	6.05	6.15	0.234	0.238	0.242
E2	3.525	3.625	3.725	0.139	0.143	0.147
E3	1.175	1.275	1.375	0.046	0.050	0.054
e	1.27 BSC			0.050 BSC		
L	0.45	0.55	0.65	0.018	0.022	0.026
L1	0		0.15	0		0.006
L2	0.68 REF			0.027 REF		
θ	0°		10°	0°		10°

UNIT: mm

NOTE 1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS. MOLD FLASH AT THE NON-LEAD SIDES SHOULD BE LESS THAN 6 MILS EACH. 2. CONTROLLING DIMENSION IS MILLIMETER.

CONVERTED INCH DIMENSIONS ARE NOT NECESSARILY EXACT.



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